## We claim:

- 1 1. A method for patterning a multilayered conductor/substrate structure 2 comprising the steps of:
- providing a multilayered conductor/substrate structure which includes a plastic substrate and at least one conductive layer overlying the plastic substrate; and
- irradiating the multilayered conductor/substrate structure with ultraviolet radiation such that portions of the at least one conductive layer are ablated therefrom.
- 1 2. The method for patterning a multilayered conductor/substrate structure 2 of claim 1 wherein the ultraviolet radiation is spatially incoherent.
- 1 3. The method for patterning a multilayered conductor/substrate structure 2 of claim 1 wherein the ultraviolet radiation has a wavelength in the mid-UV range.
- 1 4. The method for patterning a multilayered conductor/substrate structure 2 of claim 1 wherein the irradiating step comprises employing an excimer laser to ablate 3 portions of the at least one conductive layer.
- The method for patterning a multilayered conductor/substrate structure of claim 4 wherein the step of employing the excimer laser comprises controlling the excimer laser in consideration of how well the at least one conductive layer absorbs radiation at particular wavelengths.
- 1 6. The method for patterning a multilayered conductor/substrate structure 2 of claim 4 wherein the step of employing the excimer laser comprises controlling the 3 excimer laser to image a pattern from a mask onto the at least one conductive layer.
- The method for patterning a multilayered conductor/substrate structure of claim 6 wherein the pattern includes a line gap which is at least as small as 10 µm.
- 1 8. The method for patterning a multilayered conductor/substrate structure 2 of claim 1 wherein the multilayered conductor/substrate structure further comprises at

- 3 least one functional layer intermediate the at least one conductive layer and the plastic
- 4 substrate, the at least one functional layer comprising an insulating material.
- 1 9. The method for patterning a multilayered conductor/substrate structure
- 2 of claim 8 wherein the irradiating step comprises employing and controlling an excimer
- 3 laser to irradiate a portion of the at least one conductive layer such that a portion of the
- 4 at least one functional layer therebeneath heats and swells a desired amount.
- 1 10. The method for patterning a multilayered conductor/substrate structure
- 2 of claim 9 wherein the step of controlling the excimer laser comprises controlling a
- 3 fluence of the excimer laser in consideration of an ablation threshold level of the at least
- 4 one conductive layer.
- 1 11. The method for patterning a multilayered conductor/substrate structure
- 2 of claim 8 wherein the irradiating step comprises employing and controlling an excimer
- 3 laser to ablate portions of the at least one conductive layer without completely
- 4 decomposing the at least one functional layer therebeneath.
- 1 12. The method for patterning a multilayered conductor/substrate structure
- 2 of claim 4 wherein the excimer laser is part of a projection-type ablation system.
- 1 13. The method for patterning a multilayered conductor/substrate structure
- 2 of claim 12 wherein the projection-type ablation system is configured to project a
- 3 broadened laser beam.
- 1 14. The method for patterning a multilayered conductor/substrate structure
- 2 of claim 13 wherein the projection-type ablation system is configured to project the
- 3 broadened laser beam onto a patterned mask positioned over but not touching the at least
- 4 one conductive layer.
- 1 15. The method for patterning a multilayered conductor/substrate structure
- 2 of claim 14 wherein the broadened laser beam irradiates at least a 50 mm<sup>2</sup>-sized portion
- 3 of the patterned mask.

- 1 16. The method for patterning a multilayered conductor/substrate structure 2 of claim 4 wherein the excimer laser is configured to emit light at a discrete 3 characteristic wavelength.
- 1 The method for patterning a multilayered conductor/substrate structure 2 of claim 16 wherein the characteristic wavelength is 308 nm.
- 1 18. The method for patterning a multilayered conductor/substrate structure 2 of claim 16 wherein the characteristic wavelength is 248 nm.
- 1 19. The method for patterning a multilayered conductor/substrate structure 2 of claim 4 wherein the excimer laser is part of an ablation system configured to facilitate 3 a roll-to-roll production process.
- 1 20. The method for patterning a multilayered conductor/substrate structure 2 of claim 1 wherein the plastic substrate comprises polyethylene terephthalate (PET), 3 polyethylenenapthalate (PEN), polyethersulphone (PES) or polycarbonate (PC).
- 1 21. The method for patterning a multilayered conductor/substrate structure 2 of claim 1 wherein the plastic substrate comprises a polyolefin material.
- 1 22. The method for patterning a multilayered conductor/substrate structure 2 of claim 1 wherein the at least one conductive layer comprises an oxide layer.
- 1 23. The method for patterning a multilayered conductor/substrate structure 2 of claim 1 wherein the at least one conductive layer comprises an indium tin oxide 3 (ITO) layer.
- 1 24. The method for patterning a multilayered conductor/substrate structure 2 of claim 23 wherein the ITO layer is polycrystalline.

- 1 25. The method for patterning a multilayered conductor/substrate structure 2 of claim 1 wherein the at least one conductive layer comprises an alloy.
- 1 26. The method for patterning a multilayered conductor/substrate structure 2 of claim 25 wherein the alloy is an indium tin oxide (ITO) alloy.
- 1 27. The method for patterning a multilayered conductor/substrate structure 2 of claim 1 wherein the at least one conductive layer comprises a metal-based layer.
- 1 28. The method for patterning a multilayered conductor/substrate structure 2 of claim 1 wherein the at least one conductive layer comprises a silver-based layer.
- 1 29. The method for patterning a multilayered conductor/substrate structure 2 of claim 1 wherein the at least one conductive layer comprises silver and gold.
- 1 30. The method for patterning a multilayered conductor/substrate structure 2 of claim 1 wherein the at least one conductive layer is a multilayered conductive film.
- 1 31. The method for patterning a multilayered conductor/substrate structure 2 of claim 1 wherein the at least one conductive layer, where it has not been etched, has a 3 thickness between around 10 nm and around 120 nm.
- 32. The method for patterning a multilayered conductor/substrate structure
  of claim 1 wherein the at least one conductive layer has a resistivity of no greater than
  80 Ω/square.
- 1 33. The method for patterning a multilayered conductor/substrate structure 2 of claim 1 wherein the at least one conductive layer has a transmissivity of at least 80%.
- The method for patterning a multilayered conductor/substrate structure of claim 8 wherein the at least one functional layer comprises a protective layer which serves to protect layers beneath the protective layer from laser irradiation.

- The method for patterning a multilayered conductor/substrate structure of claim 34 wherein the layers beneath comprise a barrier layer which serves to protect
- 3 the plastic substrate from environmental damage.
- 1 36. The method for patterning a multilayered conductor/substrate structure 2 of claim 34 wherein the layers beneath include the plastic substrate.
- The method for patterning a multilayered conductor/substrate structure of claim 8 wherein the at least one functional layer comprises a layer of acrylic which abuts the at least one conductive layer.
- 1 38. The method for patterning a multilayered conductor/substrate structure 2 of claim 8 wherein the at least one functional layer comprises a barrier layer which 3 serves to protect the plastic substrate from environmental damage.
- 1 39. The method for patterning a multilayered conductor/substrate structure 2 of claim 38 wherein the barrier layer is inorganic.
- 1 40. The method for patterning a multilayered conductor/substrate structure 2 of claim 38 wherein the barrier layer has an oxygen transmission rate (OTR) no greater 3 than 0.05 cc/m²/day.
- The method for patterning a multilayered conductor/substrate structure of claim 38 wherein the barrier layer has a water vapor transmission rate (WVTR) no greater than 0.05 g/m²/day.
- The method for patterning a multilayered conductor/substrate structure of claim 38 wherein the barrier layer comprises a layer of SiOx which abuts the plastic substrate.
- 1 43. The method for patterning a multilayered conductor/substrate structure 2 of claim 8, further comprising:

- an additional functional layer abutting a side of the plastic substrate that faces
- 4 away from the at least one conductive layer, the additional functional layer serving to
- 5 provide structural protection and/or environmental protection for the plastic substrate.